

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
501268.01APPLICATION NO. 10/612725
~~Not Yet Assigned~~

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT(S)
Leonard ForbesFILING DATE 7/1/03
~~Concurrently herewith~~GROUP ART UNIT 2875
~~Not Yet Assigned~~





U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AK							
	AL							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AM	Cappelletti, P. et al., "Failure Mechanisms of Flash Cell in Program/Erase Cycling", <i>IEEE</i> , 1994, IEDM-94, pp. 291-294.
	AN	Guan, Huinan et al., "On Scaling of SST Split-Gate Flash Memory Technologies", Department of Electrical and Computer Engineering, University of California, Irvine, Final Report 1998-1999 for MICRO Project 98-080.
	AO	Pavan, Paolo et al., "Flash Memory Cells - An Overview", <i>Proceedings of the IEEE</i> , Vol. 85, No. 8, August 1997, pp. 1248-1271.
	AP	Seo, Jin-ho et al., "Charge-to-Breakdown Characteristics of Thin Gate Oxide and Buried Oxide on SIMOX SOI Wafers", <i>Journal of the Electrochemical Society</i> , Vol. 144, No. 1, January 1997, pp. 375-378.

EXAMINER

DATE CONSIDERED

* EXAMINER:

initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).